Model 870, Dynamic Beta Transistor Tester

MODEL 870
DYNAMIC BETA TRANSISTOR
TESTER

TECHNICAL DATA

1. Power Supply requirements: 105-125V, 50-70 cps AC

2. Power Consumption: 35 watts at 115V

3. Meter Scales:

I_{CBO}	0-100
BETA	0-100
	0-300
I_C	0-2
	0-5
V_{CE}	0-5

4. Ranges:

I_{CBO}	0-100 μa
	0-1 MA
	0-10 MA
V_{CE}	0-5 V
I_C	0-5 MA
	0-200 MA
	0-2 A

5. Meter

    Sensitivity - 100 μa, 100 MV

6. AC Test Signal

    1000 cps sine wave, variable from 2.5 μa to 10 μa
    Calibration setting at 5 μa

7. Tube Complement

	Tube	Function
V1	6X4	Power Rectifier
V2	OB2	Voltage Regulator
V3	12AT7	1/2 - 1000 cps phase shift oscillator
		1/2 - cathode follower
V4	6AW8	AC Bridge

II   DESCRIPTION

II.   1.   Purpose

The Hickok Model 870, DYNAMIC BETA TRANSISTOR TESTER, is designed to test all small, medium power, and power transistors under typical operating conditions. The versatile features of the Model 870 permit an excellent test of switching type transistors.

2.   General Description

The Model 870 offers the features of two separate transistor test instruments:

a.   An AC BETA TESTER (Small Signal Test)
b.   A DC BETA TESTER (Medium and Large Signal Test)

For ease of operation the front panel of the instrument has been divided into two major sections. The AC BETA section on the left side, and the DC BETA section on the right side of the front panel. Each section is clearly marked by a surrounding borderline. All receptacles and controls pertaining to each section are grouped within this area.

All operating controls common to both the AC and the DC section are located outside of the borderlines.

The instrument may be operated with any data taken from a transistor handbook, specification sheet or chart.

For quick and convenient reference, a rollchart listing all essential test information has been included in the instrument. For a small fee, replacement charts will be made available.

A large meter, the dials of which are clearly marked, permits excellent readability. All parameters are made variable over a wide range to make the Model 870 a versatile, reliable and accurate test instrument.

3.   Functional Description

The Model 870 is designed to perform the following functional tests:

a. I_{CBO} Collector cutoff current

b.   AC BETA   Small signal current transfer ratio at 1000 cps

c.   DC BETA   DC current transfer ratio

d. I_{CEO})
)
e. I_{CES})   Collector leakage currents
)
f. I_{CER})

g. $V_{CE(sat)}$ Collector saturation voltage

h.   AC Input Impedance
       at given operating point

III   THEORY OF OPERATION

III.   A thorough understanding of the theory behind the operation of any instrument will enable the user to obtain greater utility and satisfaction from the instrument. For this reason a brief description of the principal circuits of the instrument and diagrams of the basic test circuits are given.

1.   The power supply:

To meet the rather complex power requirements of the Model 870, the power supply consists of 3 sections.

a.   The intermediate voltage supply
b.   The low voltage supply
c.   The charging circuit

(1) The intermediate voltage supply consists of the power transformer, a rectifier tube, type 6X4, a 1N1695 silicon rectifier, two pi-type filter networks and an OA2 regulator. The latter is installed to assure good stability of the highly sensitive AC Bridge circuit.

(2) The low voltage supply employs two nickel cadmium rechargeable batteries, 5V 0.800 at 6 volts and a 5V 0.080 at 6 volts of nominal voltage. These batteries are used to give excellent reliability and long life.

(3) The charging network consists of the charging transformer T2, an SD91 silicon rectifier and four resistors, R56, R60, R61 and R62 which filter and limit the charging current.

2.   The Audio Oscillator:

The AC test signal is generated by a phase shift oscillator using 1/2 of V3, 12AT7. This signal is fed into an impedance converter, cathode follower, stage which utilizes the other 1/2 of V3.

3.   The AC Bridge:

The AC Bridge circuit consists mainly of two high gain amplifier stages, (6AW8), and a crystal diode bridge detector. The circuit is highly degenerative to provide for excellent stability. The input sensitivity of the bridge amplifier is 50 MV P-P or 17.6 MV RMS for full deflection of the meter.

4.   The Metering Circuit:

The indicator used in the Model 870, a 66K type meter, has a sensitivity of 100 μa, with an internal resistance of 1000 ohms. For the purpose of meter protection against overloading, a silicon diode, type SD91, is connected across the meter terminals. This diode will conduct and bypass any excess current that would cause damage to the meter.

5.   Selectors and Controls:

a.   Test Selector

As mentioned in the general description, the tester has been divided into an AC BETA section and a DC BETA section. The setting of the TEST SELECTOR makes the choice between the AC BETA test on the left side of the instrument (position 1) or DC BETA test on the right side of the instrument panel. (Position

2 and 3). The TEST SELECTOR in position 1 activates the AC BETA test section while disabling the DC BETA test section. The TEST SELECTOR in position 2 or 3 disables the AC BETA test section.

b. Type Selector

The TYPE SELECTOR is a reversing switch which changes the polarity of the voltages applied to the transistor under test.

c. V_{CB} Selector

The V_{CB} switch is a step selector which varies voltage between collector and base in equal steps of 5V from 0-100V. The V_{CB} selector is used for the I_{CBO}, I_{CEO}, I_{CES} and I_{CER} test only.

d. Battery Charge Selector

The battery charge selector controls the charging of the nickel cadmium batteries used as the collector and base voltage source. In the OFF position of the BATTERY CHARGE selector the charging network is disconnected. In the TRICKLE position the batteries are charged at a low rate, at which the batteries will be maintained in a fully charged state. The trickle charge may be left on indefinitely. The HIGH RATE position is for recharging purposes only. In the TEST position of the BATTERY CHARGE selector a test of the battery voltage is obtained. NOTE: See charging instruction on page 16.

e. Operate switch "A".

The push button "A", PRESS TO OPERATE, is the actuating switch for the tests. No test voltage to any element of the transistor under test is applied until the push button "A" is depressed. All settings preparing the instrument for a test can be made without any danger of damaging the transistor to be tested by any accidental missetting.

f. Push button switch "B".

Push button "B" actuates a dividing network which increases the sensitivity of the indicating network and thus changes the ranges of the meter. The changes performed by the pushbutton switch "B" are:

	From	To
BETA	0-300	0-100
CBO	0-10 MA	0-1 MA

NOTE: Unless otherwise noted all controls discussed below pertain to both the AC and DC BETA sections.

g. AC and DC FUNCTION Selectors

The AC or DC FUNCTION selector gives choice of the 5 test positions, I_{CBO}, V_{CE}, I_C, BETA CAL and AC or DC BETA. The limits of the respective ranges are marked in each position of the FUNCTION selector.

h. I_C ADJ. control

The I_C ADJ. control varies the current in the base circuit and thus controls the

current flowing in the collector circuit. The current circulated in the collector circuit is indicated by the meter and is read on the I_C dials. The I_C ADJ. controls shall be operated only when the FUNCTION selector is in the I_C position.

i. AC-DC BETA CAL control

This control is to be operated only when the respective function selector is set to the CAL position. The AC BETA CAL control calibrates the AC test signal necessary for the AC BETA test. The DC BETA CAL control sets the metering circuit to the proper sensitivity. The calibration point for both the AC and the DC BETA CAL is a set line located at 20% of full deflection of the meter.

6. Receptacles:

For the purpose of clear separation of the AC and the DC BETA section, two sets of receptacles have been provided. Each side has a socket for most common small transistors and a set of colored and marked terminals identified by E for Emitter, B for Base and C for Collector. The three alligator clips enable the user to quickly connect any type of transistor.
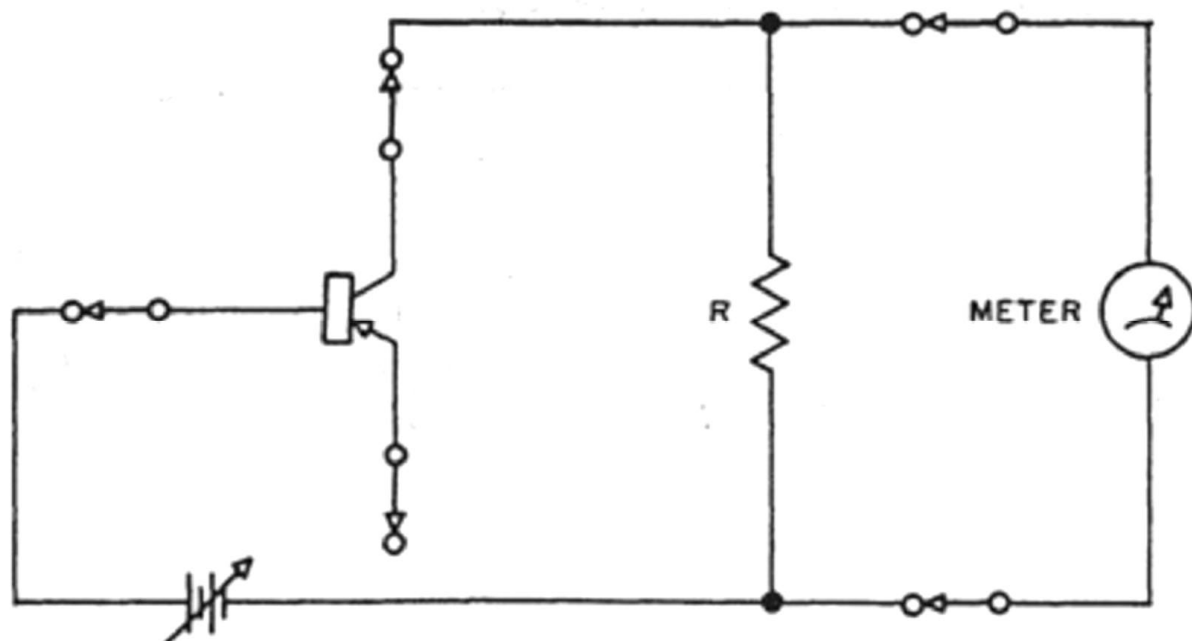
7. TEST circuits:

NOTE: To show the principle of operation, the test circuit diagrams are greatly simplified.

a. I_{CBO} Test Circuit

In the I_{CBO} test, a reverse voltage is applied between the collector and the base of the transistor under test. The emitter is open circuited.

A meter is connected in series with the collector to indicate an I_{CBO} current range of 0-100 μa. In the I_{CBO} ranges of 0-1 MA and 0-10 MA the meter is connected in parallel to a metering resistor, R. See Figure 1.
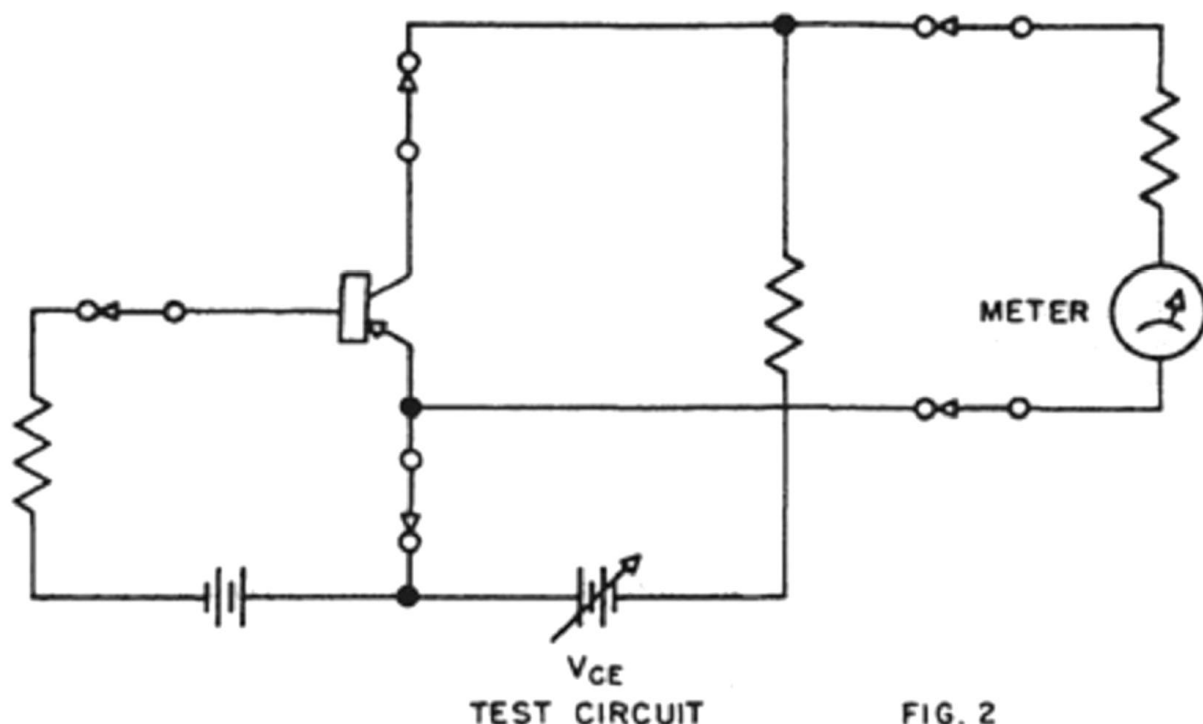

I_{CBO} (I_{CO})
TEST CIRCUIT   FIG. I

b. **V_{CE} Test Circuit**

For the V_{CE} test the indicator is converted to a voltmeter to monitor the voltage between the collector and the emitter. The collector voltage is continuously variable by the V_{CE} control, the range of which is 0-5 V. See Figure 2.


V_{CE}
TEST CIRCUIT   FIG. 2

c. **I_C Test**

To monitor the collector current I_C, a resistor, R, is switched into the collector circuit. The voltage drop across R is measured and indicated by the meter. Since the voltage drop across R is directly proportional to the current flowing through it, the dial is marked as a function of the current to permit a direct reading of the collector current I_C. See Figure 3.

I_C
TEST CIRCUIT   FIG. 3
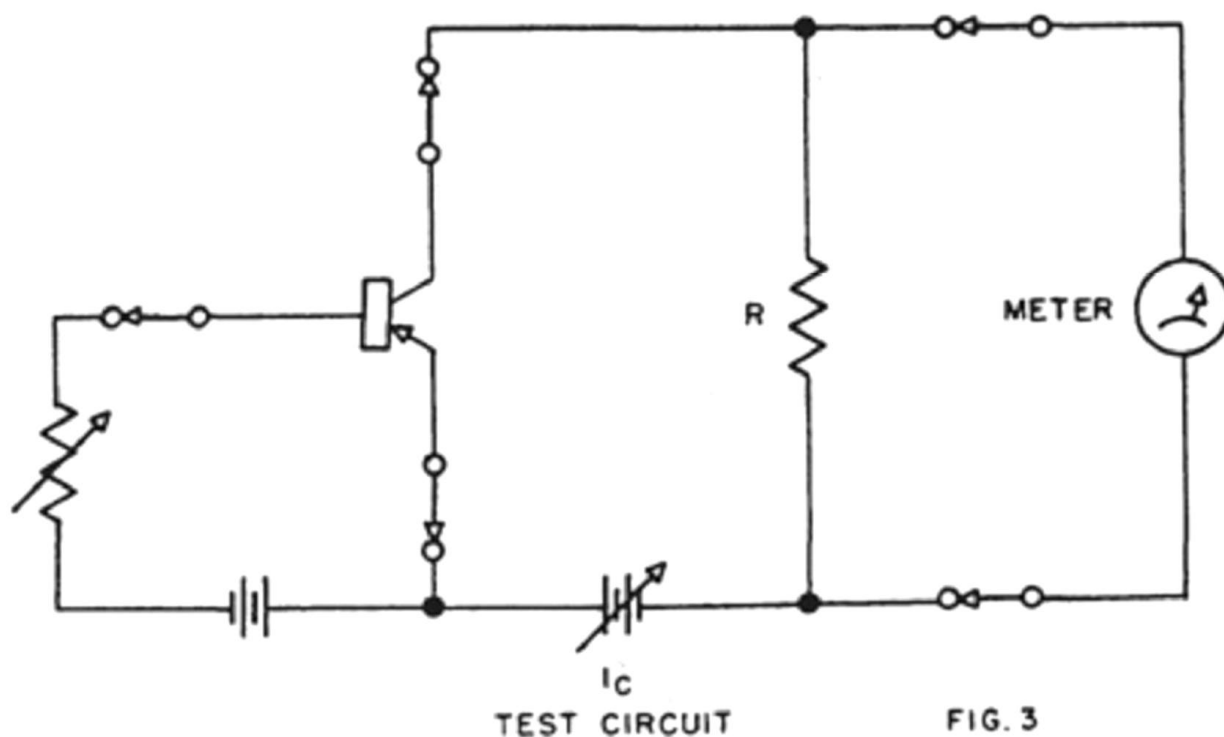
d. __AC BETA Cal.__

To obtain an accurate reading in the AC BETA test, the input test signal must be carefully adjusted to the calibration point. This is achieved by adjusting the AC BETA calibration control. At the calibration set line, the output of the audio oscillator is set to 1V peak to peak. In the AC BETA test the 1V, 1000 cps signal will produce a 5 μa AC current flow in the base of the transistor under test. See Figure 4.
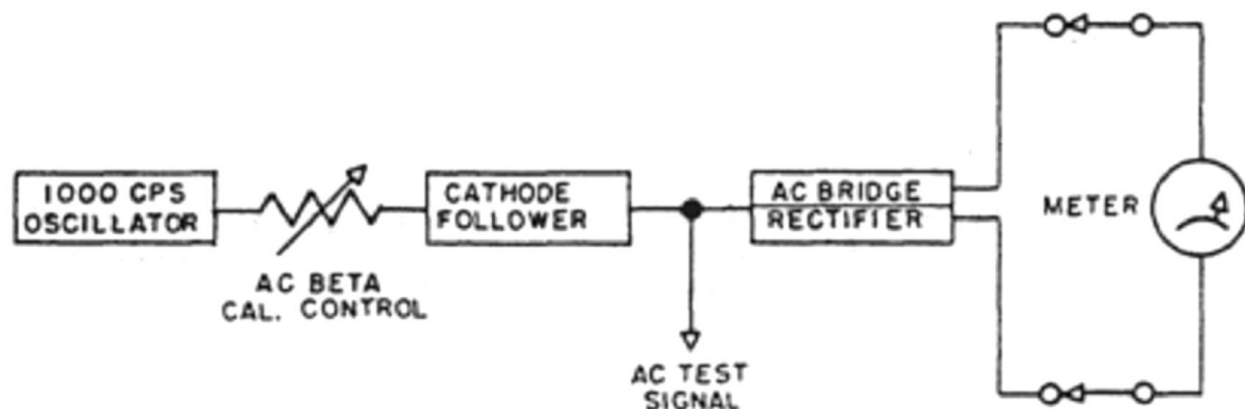

AC BETA CAL. CIRCUIT   FIG. 4

e. __AC BETA Test__

The calibrated 5 μa of test current circulated in the base will cause a current flow of I_B x BETA in the collector. To meter this I_C current a resistance R is connected in series with the collector. The AC signal developed across this resistor is amplified by the AC Bridge amplifier, rectified and then fed to the metering circuit. The meter dial is marked as a function of beta to permit a direct reading of the AC BETA. See Figure 5.
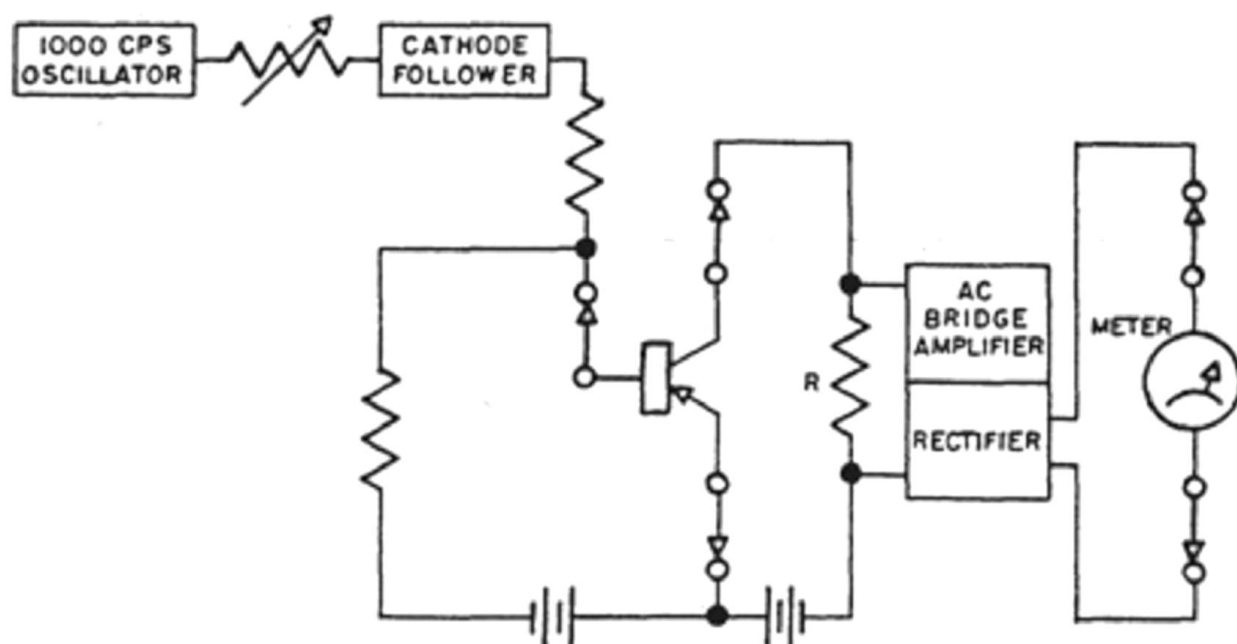
AC BETA TEST CIRCUIT   FIG. 5

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f. DC CAL and DC BETA

To illustrate the operation of the DC CAL and the DC BETA test circuit more clearly, the same are discussed together and will be shown in one diagram. Since the DC BETA is defined as the ratio of the collector current to the base current, the beta may be determined by comparing the collector current to the base current. A resistor is connected in series with both the base and the collector, the values of which are fixed in a known ratio. The voltages developed across these resistors are proportional to the current flowing through the same. The higher the DC BETA, the larger is the voltage developed across the collector resistance.

The meter dial is marked as a function of the DC BETA to permit a direct reading of BETA.

DC BETA CALIBRATION

As shown in the diagram in figure 6, R1 is used to monitor the base current of the transistor under test. By adjusting the potentiometer, R3, the calibration point is found by varying the sensitivity of the metering network.

To monitor the DC BETA, the metering circuit, the sensitivity of which has been set in the DC BETA CAL, is connected across the collector resistance, R2. Since the value of R2 is chosen in a known ratio to the value of R1, the meter reading obtained is the DC current ratio or the DC BETA of the transistor under test. See Figure 6.
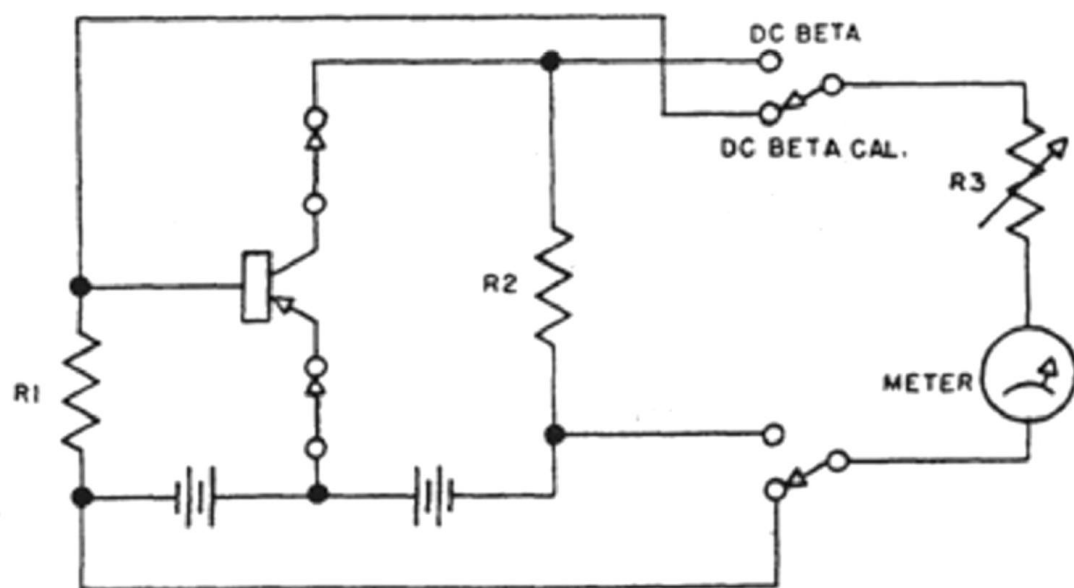
DC BETA & DC BETA CAL.
TEST CIRCUIT   FIG. 6

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IV. OPERATION

V.   To prepare the instrument for operation, follow the charging instruction on page 16 of the instruction booklet.

For operation, connect the instrument linecord to a 105-125V, 60 cps AC source.

Set the power switch to the ON position and allow sufficient time for warm-up of the instrument. (Approximately 15 minutes). This will assure stable operation.

NOTE: Before attempting any specific test, the V_{CE} control, as well as the I_C Adj. controls, must be set to the 0 or minimum position to prevent any possible damage to the transistor to be tested.

For the purpose of quick reference, the bottom view of the most common types of transistors are shown in Figure 7.
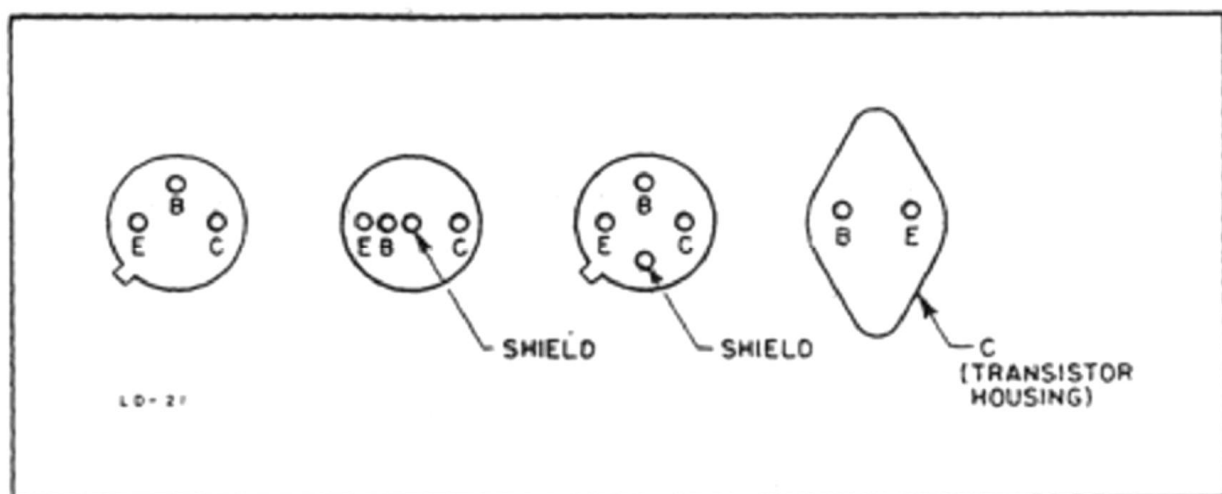
1.   THE ROLLCHART

To provide for a quick and reliable reference, a rollchart has been installed in the Model 870. All the essential test information is grouped and listed in logical sequence from left to right. The rollchart column heading is divided into 4 groups of information:

　　　　1.　General Information

　　　　　　a.　Transistor
　　　　　　b.　Type
　　　　　　c.　Test

　　　　2.　I_{CBO} test data

　　　　　　a.　Maximum I_{CBO}
　　　　　　b.　V_{CB} test voltage

The maximum I_{CBO} is the highest permissible collector leakage current specified by the transistor manufacturer. Any transistor with less than the maximum I_{CBO} may be considered good in this respect.

　　　　3.　Beta test data

a. V_{CE} Test voltage

b. I_C collector test current

    Minimum   )

c. Typical   ) BETA

    Maximum)

The BETA of a transistor may deviate considerably from its typical value. For that reason some transistor manufacturers will give minimum or maximum limits in addition to the typical value of BETA. Others will list the minimum or typical BETA only. If the minimum BETA is not given, it may be approximated to be about 50% of its typical beta value.

4. NOTES

To test some transistors with unusual characteristics a special setup becomes necessary. The essential information for the setup will be given in the notes. The notes are designated by numbers or symbols in the note column, the meaning of which may be found at the top of the rollchart or in this instruction book.

NOTE #1   Set the "Calibration" to 40. Divide obtained "Beta" by 2.

NOTE #2   Make "I_{CBO}" test in the "AC Beta" section.

NOTE #3   Set the "calibration" to 10. Double obtained "Beta" reading.

NOTE #4   Complementary pair.
                        PNP - identified by red
                        NPN - identified by black dot

NOTE #5   Connect B1 and B2 to the base terminal and test as triode

NOTE #6   Perform "I_{CER}" test. Reverse the emitter and base leads. Connect a 200 ohm resistor between the emitter and base terminals.

NOTE #7   Perform "I_{CER}" test. Reverse the emitter and base leads. Connect a 30 ohm resistor between the emitter and base terminals.

NOTE #8   Perform "I_{CER}" test. Reverse the emitter and base leads. Connect a 10K ohm resistor between the emitter and base terminals.

The Principle tests performed by the Model 870 are:

1. The I_{CBO}

2. The AC BETA test

3. The DC BETA test

NOTE: In the following operating instruction, reference will be made to the rollchart installed in the instrument. However, any transistor manual may be used as test information. To operate the Model 870 with any other reference than the rollchart, refer to Page 13 in this booklet.

To make any test, perform the following preliminary steps.

A. Find the TRANSISTOR number by dialing the rollchart.
B. Set the TYPE selector to the position indicated, either PNP or NPN.
C. Set the TEST SELECTOR to position 1, 2 or 3, as indicated in the rollchart.
D. Connect the transistor to the proper terminals; use left side terminals for test #1, right side terminals for tests 2 and 3. Choose between socket, terminals or test leads, depending on the physical nature of the transistor to be tested.

1. The I_{CBO} test

By definition, the I_{CBO} (sometimes referred to as I_{CO}) is the collector leakage current with a given reverse voltage applied to the collector and the emitter open circuited.
To perform an I_{CBO} test, proceed as follows:

a. Set the Function Selector of the side on which the test is performed to the I_{CBO} position.
b. Set the VCB selector to the voltage listed under the V_{CB} symbol of the rollchart.
c. Press the A button to operate and read on the I_{CBO} scale of the meter.

The ranges of I_{CBO} current are:

AC BETA	0-100 μA
DC BETA	0-10 MA
Press Button B for	0-1 MA

2. AC or DC BETA test

a. Set the FUNCTION selector (of the section at which the test is to be performed) to the V_{CE} position.
b. Press button A to operate and adjust the V_{CE} control to the voltage shown in the roll-chart.
c. Set the FUNCTION selector to the I_C position.
d. Push button A and adjust the I_C control for the I_C test current given in the rollchart.

The I_C ranges are:

AC BETA TEST #1 (left side)	0-5 MA
DC BETA TEST #2 (right side)	0-200 MA
TEST #3	0-2 A

NOTE: When testing power transistors, step b and d may have to be repeated until no change as a result of a made adjustment is noticed.

e. Set the FUNCTION selector to the BETA CAL. position.
f. Press button A and adjust the BETA CAL. control to the calibration set line located at 20% of full deflection of the METER dial.
g. Set the FUNCTION selector to the AC or DC BETA position, depending on which test is performed.
h. Press button "A" to operate and read the BETA directly on the BETA scale of the meter dial.

NOTE: If the BETA is less than 100 and better readability is desired, press button B and read on the BETA range of 0-100.

Caution: Return the I_C ADJ. control to the minimum position after the test has been completed.

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ADDITIONAL TESTS

The Model 870 is primarily designed to perform the basic tests, I_{CBO}, AC BETA, and DC BETA which determine the quality of a transistor. However a number of other tests which are not conventional may be performed by using the Model 870. These additional tests are:

1. I_{CEO}

2. I_{CER}

3. I_{CES}

4. AC input impedance

5. $V_{CE(sat)}$ (Collector saturation voltage

2. The I_{CEO} TEST

By definition, I_{CEO} is the collector leakage current with the collector reverse biased and the base open-circuited.

In general, the I_{CEO} leakage current is considerably larger than the I_{CBO}. To perform an I_{CEO}, proceed as follows:

a. Set the FUNCTION selector to the I_{CBO} position.
b. Reverse the emitter and base leads when connecting the transistor to the receptacle.
c. If no handbook for reference is available, set the V_{CB} selector to approximately 75% of the voltage indicated under the V_{CB} symbol on the rollchart.
d. Press button "A" to operate and read the I_{CEO} directly on the I_{CBO} dial of the meter.

   NOTE: If at any time the I_{CEO} of a transistor tested in position 1 of the TEST SE-LECTOR (AC BETA) exceeds 100 μA, remove the transistor and test it on the DC BETA side of the instrument panel, the I_{CBO} ranges of which are 0-1 M, 0-10 MA.

3. I_{CER} TEST

By definition, I_{CER} is the collector leakage current measured with the collector reverse biased and a resistor of generally 10K connected between the base and the emitter of the transistor under test. To perform an I_{CER} test, connect a 10K ohm resistor between the base and the emitter terminals which are used for the test and proceed as if performing an I_{CEO} test.

4. I_{CES} TEST

By definition, I_{CES} is the collector leakage current with the collector reverse biased and the base shorted to the emitter.

To perform an I_{CES} test, connect a short jumper between the emitter and the base terminal and proceed as if performing an I_{CEO} test.

5. AC INPUT IMPEDANCE TEST

NOTE: The input impedance is a function of the operating condition and will vary considerably with changes of base and collector currents.

To check the AC input impedance of a transistor:

a. Prepare a network consisting of a 100 μf capacitor and a 10K ohm potentiometer in series.

b.   Perform an AC BETA test as described in section V, 2 a-f and leave the test setup unchanged after completing the test.

c.   Connect the network prepared in step a between the emitter and the base terminal.

CAUTION: Observe the polarity of the capacitor. When testing a PNP transistor, connect the network with the negative pole of the capacitor towards the base terminal. If a NPN transistor is to be tested, connect the positive pole to the base terminal.

d.   Push button "A" to operate and adjust the 10 K ohm potentiometer until the previously obtained beta reading is reduced to one half.

e.   Remove the network from the terminals and measure the resistance of the potentiometer with an ohmmeter. The obtained reading is the AC input impedance of the transistor under test.

6. $V_{CE(sat)}$ COLLECTOR SATURATION VOLTAGE

By definition, the $V_{CE(sat)}$ is a collector voltage point for a given base current at which the collector current will not increase considerably when the collector voltage is increased.

NOTE: In testing switching type transistors it may be desirable to determine the $V_{CE(sat)}$.

To perform a V_{CE} test proceed as follows:

a.   Perform a Beta test as described in section V, 2 a-f.

b.   While pressing down pushbutton "A" turn the V_{CE} control in counterclockwise direction until the beta reading drops off sharply.

c.   Locate this drop-off point (knee) as accurately as possible by adjusting the V_{CE} control slightly.

d.   Set the FUNCTION selector to the V_{CE} position.

e.   Press down pushbutton "A" and read the voltage on the V_{CE} dial. The obtained reading is the collector saturation voltage V_{CE} (sat) at a given base current.

OPERATING THE MODEL 870 USING TEST INFORMATION OTHER THAN THE ROLLCHART

In the preceding description of operation the rollchart installed in the instrument has been used as reference. It is understood, however, that it is impossible to include all transistors in the rollchart. To account for this fact, the Model 870 has been designed to permit any test setup by reference to test information given in handbooks, manuals or specification sheets.

When using a reference other than the rollchart simply follow the outline given by the rollchart heading using the test data from the reference book.

OPERATING HINTS

In general, the ranges of the Model 870 will suffice for the testing of transistors with normal characteristics, however, transistors with abnormal characteristics may deviate considerably from their normal values of beta, input impedance, collector and base current, etc. As a direct effect of one of those abnormal conditions, the instrument ranges may not be wide enough to permit a direct test.

To perform a test where these conditions exist, observe the following hints:

Condition 1

<u>The calibration point cannot be reached by adjusting the CAL control.</u>

If the CAL SET point at 20 cannot be reached by adjusting the BETA CAL control, set the CAL control to either 10 or 40 depending on which point may be reached. The Beta reading must be multiplied by 2 for a calibration setting of 10 ($\frac{1}{2}$ of original CAL setting). If the calibration has been set to 40 (twice the original setting) the obtained beta reading must be divided by 2 to determine the true beta.

For Example:

    a.   The calibration has been set to 2 x the indicated value:

$\frac{20}{\text{Cal. Set line}}$	X	$\frac{2}{\text{Multiplier}}$	=	$\frac{40}{\text{New Set Point}}$

The BETA reading obtained with the calibration setting of 40 is found to be 100.

To determine the correct BETA, 100 is divided by 2.

$\frac{100}{\text{BETA Reading}}$	÷	$\frac{2}{\text{Divider}}$	=	$\frac{50}{\text{True Beta}}$

    b.   The calibration is set to 1/2 of its original setting at 20. The set point is 10.

20 Cal. Set line	÷	2 Divider	=	10 New Set Line

The BETA reading with the calibration set to 10 is found to be 30.

The true BETA is given by the relationship

30 BETA reading	X	2 Multiplier	=	60 True BETA

As is easily seen from the examples above, the true beta varies inversely proportional to the change of the calibration from its original setting.

Condition 2

<u>The BETA of a transistor is higher than 300 and therefore causes the meter to deflect higher than full scale.</u>

If at any time a transistor indicates a beta of more than 300,

    a.   Set the FUNCTION Selector to the BETA CAL position.

    b.   By adjusting the BETA CAL control, set the calibration to $\frac{1}{2}$ of its CAL SET point at 20, or to 10 div.

    c.   Set the FUNCTION selector to the BETA position.

    d.   Press button "A" and determine the true BETA by multiplying the BETA reading obtained by 2.

Condition 3

<u>The I_C test current cannot be reached by adjusting the I_C control.</u>

If an AC BETA test is performed (position 1 of the TEST SELECTOR, 0-5 MA) and the given I_C current cannot be reached by adjusting the I_C ADJ. control, test the transistor at the highest I_C current that may be reached. If the specified I_C current is larger than 5 MA:

    a.   Remove the transistor from the AC BETA section and connect it to the DC BETA section.

    b.   Set the TEST selector to position #2, 0-200 MA, and perform a DC BETA test using the data given for the AC BETA test.

Condition 4

If a DC BETA test is performed in position #2, 0-200, of the TEST SELECTOR, and it is noted that the IC test current cannot be reached by adjusting the I_C control:

    a.   Set the test selector to position #3, 0-2 A.
    b.   Perform the DC BETA as suggested.

Condition 5

If a DC BETA test is made in position #3, 0-2A, of the TEST SELECTOR and the I_C test current cannot be reached by adjusting the I_C ADJ., test the transistor at the highest possible I_C.

In general, if conditions 3, 4 or 5 exist, it may be assumed that the BETA of the transistor under test is very low. To explain this interrelation more clearly, it should be understood that the I_C (collector current) is a function of the base current multiplied by the BETA of the transistor under test.

Since the base current is variable over a given range, the collector current will be confined to a range given by the following relationship.

    Min I_C = Min I_B x BETA   Max I_C = I_B x BETA

The ranges of base current variation by adjusting the I_C control are:

	Min	Max
Pos. 1 of the TEST SELECTOR (AC BETA section)	1.7 μa	60 μa
Pos. 2 of the TEST SELECTOR (DC BETA section)	120 μa	1.6 MA
Pos. 3 of the TEST SELECTOR (DC BETA section)	1.02 MA	40 MA

NOTE: These given limits may vary slightly because they are affected by the input impedance of the transistor under test.

7.   AC BETA test signal

The AC BETA test signal used in the Model 870 is 5 μa in the Calibration setting. However, if so desired, the AC test signal may be changed to either 2.5 μA or 10 μA by either reducing the calibration to $\frac{1}{2}$ or increasing it to 2 times its usual setting. Since the BETA reading changes proportionally to the change of the test current circulated in the base, the true BETA is determined in the following way:

a. If the calibration is set to one half of its normal setting (2.5 µA), multiply BETA reading by 2 to obtain true beta.

b. If the calibration has been set to 2 x the normal setting (10 µA), divide obtained BETA reading by 2.

8. Detecting Shorted Transistors

The following inter-element shorts may develop in a transistor:

1. EMITTER to base short.
2. BASE to collector short.
3. EMITTER to collector short.

The shorts listed above may be detected by the following reactions of the tester:

1. EMITTER to base short.
   Low or no I_C reading with the I_C control set to the maximum position. Adjustment of the I_C ADJ has little or no effect on the I_C current.

2. BASE to COLLECTOR short.
   Meter will deflect full scale if an I_{CBO} test is performed.

3. EMITTER to COLLECTOR short.

   a. When attempting to set the V_{CE} voltage, a low or no reading is obtained with the V_{CE} set to the maximum position.

   b. When setting the I_C test current, a high reading is obtained which cannot be decreased by the I_C Adjust.

9. Relationship Between ALPHA and BETA

By definition:

BETA is the forward current transfer ratio of a transistor in the common emitter configuration.

ALPHA is the forward current transfer ratio of a transistor in the common base configuration.

A definite relationship between ALPHA and BETA is established in the following formula:

$$BETA \quad = \quad \frac{Alpha}{1 - Alpha}$$

$$ALPHA \quad = \quad \frac{Beta}{1 + Beta}$$

By applying one of the given formulae above, the value of one parameter (BETA or ALPHA) may be calculated if the value of the other is known.

10. Charging Instructions

To insure proper function of the Model 870, the rechargeable batteries used as the collector and the base voltage sources must be kept in a fully charged state.

To charge batteries from fully discharged state:

a.   Set the BATTERY CHARGE selector to the HIGH RATE position.
b.   Connect the instrument line cord to a 105-125V AC line source.
c.   Allow at least 20 hours of continuous charging time to fully charge the batter

NOTE: The power ON-OFF switch does not activate the charging network and th
not be set to the ON position to charge batteries.

d.   After the batteries have been sufficiently charged, set the BATTERY CHARGI
the TRICKLE position. This moderate charge will keep the batteries in a f
state.

NOTE: To assure long life of the batteries, it is favorable to keep them (once c
charged state.

The TRICKLE charge may be left on indefinitely. The HIGH RATE charge is fo
purposes only and should not be left on in excess of 60 days. Permanent damage to
may result from constant overcharging. If the instrument has been inoperative fo
longer than 1 month, recharge batteries before performing any tests.

e.   To test the condition of the batteries, set the BATTERY CHARGE SELI
TEST position. The voltage indication should never be less than 6. 15V
battery check line on the lowest arc of the meter dial.

If the voltage is low, set the BATTERY CHARGE selector to the HIGH R
and allow appropriate time for recharging. After the batteries have bee
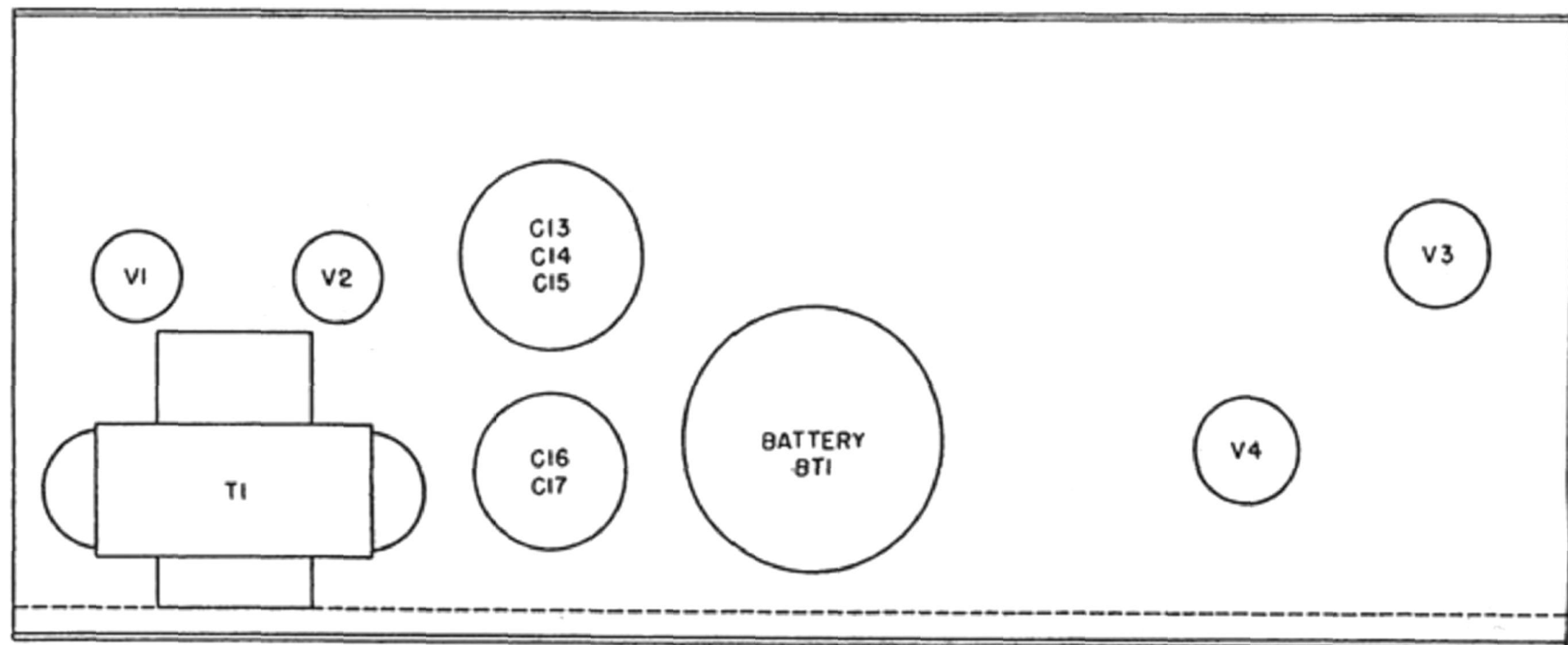ly charged, return the BATTERY CHARGE selector to the TRICKLE cha

V.   MAINTENANCE

VI. In general, the Model 870, DYNAMIC BETA TRANSISTOR TESTER will give l
rupted service. The Model 870 is a complex and specialized instrument. N
yond tube replacement should be attempted. If an instrument cannot be repair
replacement, it is recommended that the instrument be returned to the fa
authorized Hickok service station.
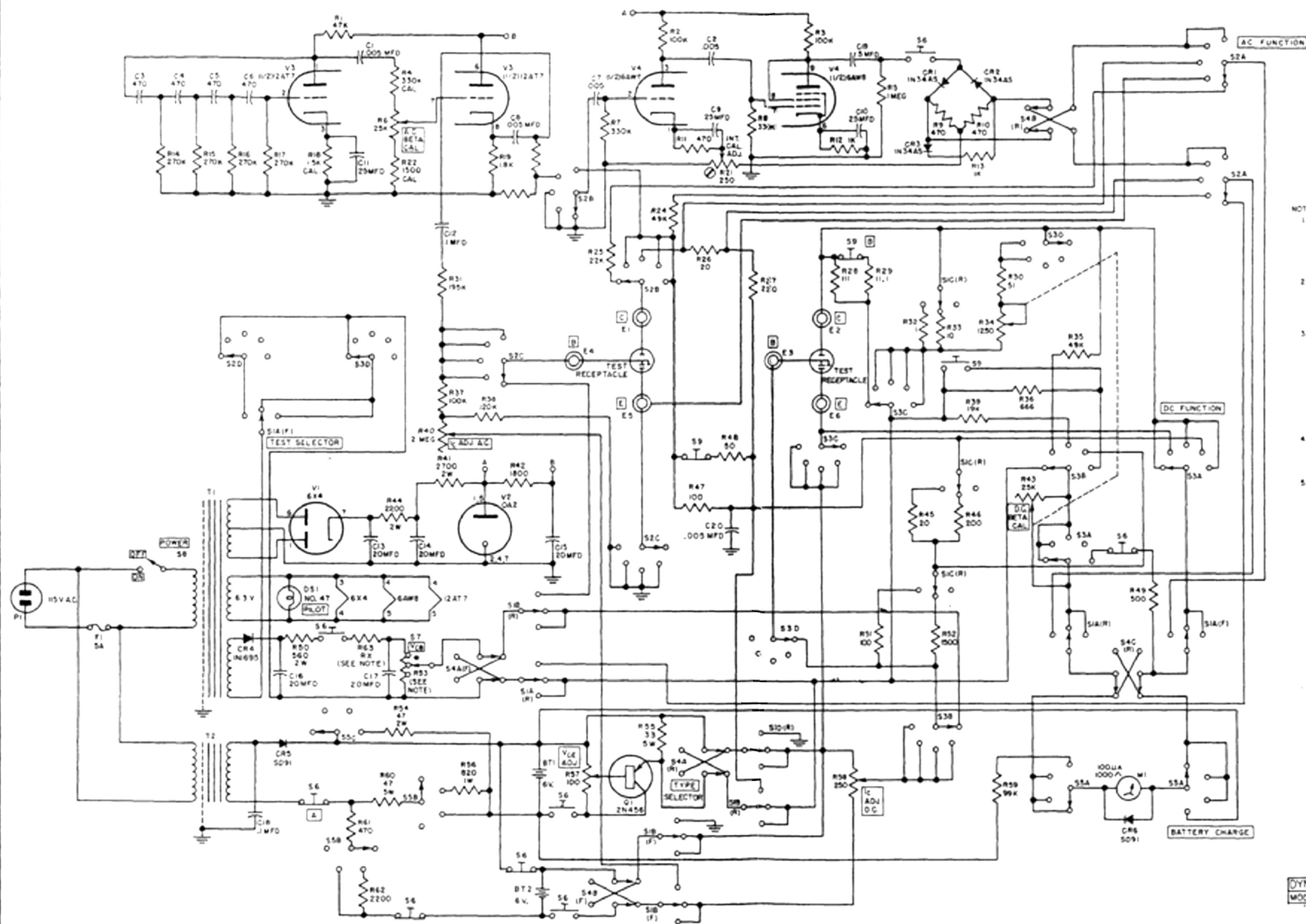
1.   Fuse Replacement

In the event of fuse failure, the instrument should be checked for shorts befor
is installed. For fuse replacement, use . 5A SLOW BLOW value only.

Figure #8 is included to aid in locating tubes for replacement.

LOCATION OF TUBES
FIG. - 8

AC FUNCTION

DC FUNCTION

AC FUNCTION

BATTERY CHARGE

TEST RECEPTACLE

TEST SELECTOR

POWER

115 V AC

NOTE
1. UNLESS OTHERWISE INDICATED, RESISTANCES ARE IN OHMS (Ω), CAPACITANCES ARE IN MMF
* R53 IS COMPOSED OF 20 (100Ω) RESISTORS WIRED IN SERIES
2. ☐ = EQUIPMENT PANEL MARKING
⊘ = SCREWDRIVER ADJUST
3. SWITCHES
S1 = TEST SELECTOR
S2 = A C FUNCTION SELECTOR
S3 = D C FUNCTION SELECTOR
S4 = TYPE SELECTOR
S5 = BATTERY CHARGE SELECTOR
S6 = OPERATE
S7 = COLLECTOR VOLTAGE
S8 = POWER
S9 = MULTIPLIER
4. SWITCH DECKS ARE IDENTIFIED BY LETTERS "A", "B", "C", ETC.
(F) = FRONT CONTACTS
(R) = REAR CONTACTS
5. RX = APPROXIMATELY 150Ω, 1/2W

DYNAMIC BETA TRANSISTOR TESTER
MODEL 870 · SCHEMATIC WIRING DIAGRAM